

<b>Notice of References Cited</b>	Application/Control No. 10/799,043	Applicant(s)/Patent Under Reexamination HASHIMOTO ET AL.	
	Examiner Jeffrey T. Barton	Art Unit 1753	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	H. Sheng et al, "Nonalloyed Al Ohmic Contacts to Mg <sub>x</sub> Zn <sub>1-x</sub> O", J. Electron. Mater. 31 (7), 811-814. (2002)
	V	
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